

**AMENDMENTS TO THE SPECIFICATION**

Please amend the last paragraph on page 1 as shown below.

The number of test terminals 22 may be on the same order of magnitude as the number of input/output terminals 16, for example, from 200 to 400 terminals. Test terminals 22 as well as the connections of monitoring circuit 18 take up a significant silicon surface area, which causes an unwanted increase in the circuit cost. For this purpose, a first version of integrated circuit 10 comprising monitoring circuit 18 and test terminals 22 is produced in small quantities to adjust debug the program of microprocessor 12 or "user program". After this debugging, a version of integrated circuit 10[[ d of]] without monitoring circuit 18 and without test terminals 22 is sold. This requires forming of two versions of the integrated circuit, which requires a significant amount of work and is relatively expensive. Further, the final chip is not necessarily identical to the tested chip.--